Omer Gullu

List of Publications by Year in descending order

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		279798	315739
58	1,554 citations	23	38
papers	citations	h-index	g-index
58	58	58	1038
30	30	30	1030
all docs	docs citations	times ranked	citing authors

#	Article	IF	CITATIONS
1	Optical and structural properties of CuO nanofilm: Its diode application. Journal of Alloys and Compounds, 2010, 492, 378-383.	5.5	156
2	Fabrication and electrical characteristics of Schottky diode based on organic material. Microelectronic Engineering, 2008, 85, 1647-1651.	2.4	144
3	Photovoltaic and electronic properties of quercetin/p-InP solar cells. Solar Energy Materials and Solar Cells, 2008, 92, 1205-1210.	6.2	72
4	The effect of Schottky metal thickness on barrier height inhomogeneity in identically prepared Au/n-GaAs Schottky diodes. Semiconductor Science and Technology, 2006, 21, 1-5.	2.0	71
5	High barrier Schottky diode with organic interlayer. Solid State Communications, 2012, 152, 381-385.	1.9	64
6	Laterally inhomogeneous barrier analysis of the methyl violet/p-Si organic/inorganic hybrid Schottky structures. Applied Surface Science, 2008, 254, 3039-3044.	6.1	61
7	Electrical analysis of organic dye-based MIS Schottky contacts. Microelectronic Engineering, 2010, 87, 2482-2487.	2.4	57
8	Electrical analysis of organic interlayer based metal/interlayer/semiconductor diode structures. Journal of Applied Physics, 2009, 106, .	2.5	54
9	Electrical characterization of the Al/new fuchsin/n-Si organic-modified device. Physica E: Low-Dimensional Systems and Nanostructures, 2010, 42, 1411-1416.	2.7	49
10	Electronic properties of the metal/organic interlayer/inorganic semiconductor sandwich device. Journal of Physics and Chemistry of Solids, 2010, 71, 351-356.	4.0	47
11	Electronic parameters of high barrier Au/Rhodamine-101/n-Inp Schottky diode with organic ınterlayer. Thin Solid Films, 2012, 520, 1944-1948.	1.8	38
12	Fabrication and electrical properties of Al/Safranin T/n-Si/AuSb structure. Semiconductor Science and Technology, 2008, 23, 075005.	2.0	37
13	Electronic properties of Al/DNA/p-Si MIS diode: Application as temperature sensor. Journal of Alloys and Compounds, 2011, 509, 571-577.	5.5	37
14	DNA-based organic-on-inorganic semiconductor Schottky structures. Applied Surface Science, 2008, 254, 5175-5180.	6.1	34
15	Ultrahigh (100%) barrier modification of n-InP Schottky diode by DNA biopolymer nanofilms. Microelectronic Engineering, 2010, 87, 648-651.	2.4	34
16	Gamma irradiation-induced changes at the electrical characteristics of organic-based schottky structures. Journal Physics D: Applied Physics, 2008, 41, 135103.	2.8	31
17	DNA-modified indium phosphide Schottky device. Applied Physics Letters, 2008, 92, 212106.	3.3	30
18	Silicon MIS diodes with Cr2O3 nanofilm: Optical, morphological/structural and electronic transport properties. Applied Surface Science, 2010, 256, 4185-4191.	6.1	28

#	Article	IF	CITATIONS
19	Determination of the laterally homogeneous barrier height of thermally annealed and unannealed Au/p-InP/Zn-Au Schottky barrier diodes. Applied Surface Science, 2008, 254, 3558-3561.	6.1	27
20	Electrical characterization of organic-on-inorganic semiconductor Schottky structures. Journal of Physics Condensed Matter, 2008, 20, 045215.	1.8	25
21	Determination of the laterally homogeneous barrier height of metal/p-lnP Schottky barrier diodes. Vacuum, 2009, 83, 1470-1474.	3. 5	25
22	Electrical characteristics of the hydrogen pre-annealed Au/n-GaAs Schottky barrier diodes as a function of temperature. Applied Surface Science, 2007, 253, 7246-7253.	6.1	24
23	Determination of lateral barrier height of identically prepared Ni/n-type Si Schottky barrier diodes by electrodeposition. Physica B: Condensed Matter, 2008, 403, 2211-2214.	2.7	23
24	γ-Irradiation-induced changes at the electrical characteristics of Sn/p–Si Schottky contacts. Vacuum, 2008, 82, 789-793.	3.5	22
25	Fabrication and electrical properties of organic-on-inorganic Schottky devices. Journal of Physics Condensed Matter, 2008, 20, 215210.	1.8	21
26	Fabrication and electrical characterization of a silicon Schottky device based on organic material. Physica Scripta, 2009, 79, 035802.	2.5	21
27	The analysis of lateral distribution of barrier height in identically prepared Co/n-Si Schottky diodes. Journal of Alloys and Compounds, 2009, 486, 343-347.	5 . 5	20
28	Fabrication and electrical properties of Al/aniline green/n-Si/AuSb structure. Materials Science in Semiconductor Processing, 2008, 11, 53-58.	4.0	19
29	DNA-based organic-on-inorganic devices: Barrier enhancement and temperature issues. Microelectronic Engineering, 2008, 85, 2250-2255.	2.4	18
30	Electronic parameters of MIS Schottky diodes with DNA biopolymer interlayer. Materials Science-Poland, 2015, 33, 593-600.	1.0	18
31	Electrical characteristics and inhomogeneous barrier analysis of aniline green/p-Si heterojunctions. Journal of Materials Science: Materials in Electronics, 2008, 19, 986-991.	2.2	17
32	Temperature-dependent behavior of Ti/p-InP/ZnAu Schottky barrier diodes. Semiconductor Science and Technology, 2008, 23, 035006.	2.0	17
33	Wet chemical methods for producing mixing crystalline phase ZrO 2 thin film. Applied Surface Science, 2016, 377, 159-166.	6.1	17
34	Electron irradiation effects on the organic-on-inorganic silicon Schottky structure. Nuclear Instruments and Methods in Physics Research, Section A: Accelerators, Spectrometers, Detectors and Associated Equipment, 2008, 593, 544-549.	1.6	16
35	Analysis of the series resistance and interface state densities in metal semiconductor structures. Journal of Physics: Conference Series, 2009, 153, 012054.	0.4	15
36	Analysis of electrical and photoelectrical properties of ZnO/p-InP heterojunction. Journal of Alloys and Compounds, 2011, 509, 6631-6634.	5 . 5	15

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37	Current density-voltage analyses and interface characterization in Ag/DNA/p-InP structures. Journal of Applied Physics, 2012, 111, 044503.	2.5	14
38	Temperature dependence of current–voltage characteristics of Sn/p-Si Schottky contacts. Physica B: Condensed Matter, 2008, 403, 131-138.	2.7	13
39	Characterization of an Au/n-Si photovoltaic structure with an organic thin film. Materials Science in Semiconductor Processing, 2013, 16, 1125-1130.	4.0	13
40	Fabrication and electrical properties of Al/phenolsulfonphthalein/n-Si/AuSb structure. Vacuum, 2008, 82, 1264-1268.	3. 5	11
41	Synthesis and characterization of vanadium oxide thin films on different substrates. Journal of Materials Science: Materials in Electronics, 2017, 28, 10909-10913.	2.2	11
42	Electrical Characteristics of Co/n-Si Schottky Barrier Diodes Using ⟨i⟩l⟨ i⟩ – ⟨i⟩V⟨ i⟩ and ⟨i⟩C⟨ i⟩ – ⟨i⟩V⟨ i⟩ Measurements. Chinese Physics Letters, 2009, 26, 067301.	3.3	10
43	A study of the rectifying behaviour of aniline green-based Schottky diode. Microelectronic Engineering, 2010, 87, 187-191.	2.4	9
44	Effects of the barrier metal thickness and hydrogen pre-annealing on the characteristic parameters of Au/n-GaAs metal–semiconductor Schottky contacts. Thin Solid Films, 2008, 516, 7851-7856.	1.8	8
45	Impedance and Interface Properties of Al/Methyl-Red/p-InP Solar Cell. International Journal of Photoenergy, 2009, 2009, 1-7.	2.5	7
46	Electrical Properties of Organic–Inorganic Semiconductor Device Based on Rhodamine-101. Journal of Electronic Materials, 2009, 38, 1995-1999.	2.2	7
47	n-type InP Schottky diodes with organic thin layer: Electrical and interfacial properties. Journal of Vacuum Science and Technology B:Nanotechnology and Microelectronics, 2010, 28, 466-472.	1.2	7
48	Electronic Properties of Cu/n-InP Metal-Semiconductor Structures with Cytosine Biopolymer. Acta Physica Polonica A, 2015, 128, 383-389.	0.5	7
49	Electrical properties of safranine T/p-Si organic/inorganic semiconductor devices. EPJ Applied Physics, 2010, 50, 10401.	0.7	6
50	THE CHARACTERISTIC DIODE PARAMETERS IN Ti/p-InP CONTACTS PREPARED BY DC SPUTTERING AND EVAPORATION PROCESSES OVER A WIDE MEASUREMENT TEMPERATURE. Surface Review and Letters, 2017, 24, 1750052.	1.1	6
51	Barrier enhancement of Al/n-InP Schottky diodes by graphene oxide thin layer. Indian Journal of Physics, 2019, 93, 467-474.	1.8	5
52	Current–voltage and capacitance–voltage characteristics of Fe/p-InP Schottky barriers. International Journal of Electronics, 2010, 97, 973-983.	1.4	4
53	Room temperature l–V and C–V characteristics of Au/mTPP/p-Si organic MIS devices. EPJ Applied Physics, 2018, 82, 20101.	0.7	4
54	Barrier Modification by Methyl Violet Organic Dye Molecules of Ag/P-Inp Structures. European Journal of Interdisciplinary Studies, 2016, 2, 7.	0.1	3

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55	Dielectric spectroscopy studies on AL/p-Si photovoltaic diodes with Coomassie Brilliant Blue G-250. Applied Physics A: Materials Science and Processing, 2022, 128, .	2.3	3
56	The optical characterization of organometallic complex thin films by spectroscopic ellipsometry and photovoltaic diode application. Materials Research Bulletin, 2016, 77, 115-121.	5.2	2
57	Analysis of interface states of Al/DNA/p-Si MIS photovoltaic structures with DNA biomolecules using the conductance technique. Materials Technology, 2017, 32, 505-513.	3.0	O
58	Morphological and electrical properties of Ag/p -type indium phosphide MIS structures with malachite green organic dyes., 2022, 18, 421-430.		0